

# ZXMN2B14FH 20V SOT23 N-channel enhancement mode MOSFET with low gate drive capability

### Summary

V <sub>(BR)DSS</sub>	R <sub>DS(on)</sub> (Ω)	I <sub>D</sub> (A)
	0.055 @ V <sub>GS</sub> = 4.5V	4.3
20	0.075 @ V <sub>GS</sub> = 2.5V	3.7
	0.100 @ V <sub>GS</sub> = 1.8V	3.2

### Description

This new generation of trench MOSFETs from Zetex features low onresistance achievable with low gate drive.

### **Features**

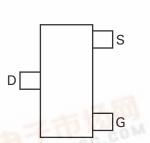
- Low on-resistance
- Fast switching speed
- Low gate drive capability
- SOT23 package

### **Applications**

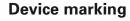
- DC-DC converters
- Power management functions DZSC.COM
- Disconnect switches
- Motor control

## **Ordering information**

Device	Reel size (inches)	Tape width (mm)	Quantity per reel
ZXMN2B14FHTA	7	8	3,000

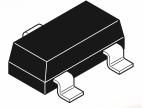


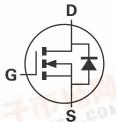
Top view



2B4







### Absolute maximum ratings

Parameter	Symbol	Limit	Unit	
Drain-source voltage	V <sub>DSS</sub>	20	V	
Gate-source voltage		V <sub>GS</sub>	± 8	V
Continuous drain current	@ $V_{GS}$ = 4.5V; $T_{amb}$ =25°C (b)	Ι <sub>D</sub>	4.3	А
	@ $V_{GS}$ = 4.5V; $T_{amb}$ =70°C (b)		3.5	
	@ $V_{GS}$ = 4.5V; $T_{amb}$ =25°C (a)		3.5	
Pulsed drain current (c)	I <sub>DM</sub>	21	А	
Continuous source current	۱ <sub>S</sub>	2.4	А	
Pulsed source current (boo	I <sub>SM</sub>	21	А	
Power dissipation at T <sub>amb</sub> =	PD	1	W	
Linear derating factor		8	mW/°C	
Power dissipation at T <sub>amb</sub>	PD	1.5	W	
Linear derating factor		12	mW/°C	
Operating and storage terr	T <sub>j</sub> , T <sub>stg</sub>	-55 to +150	°C	

### **Thermal resistance**

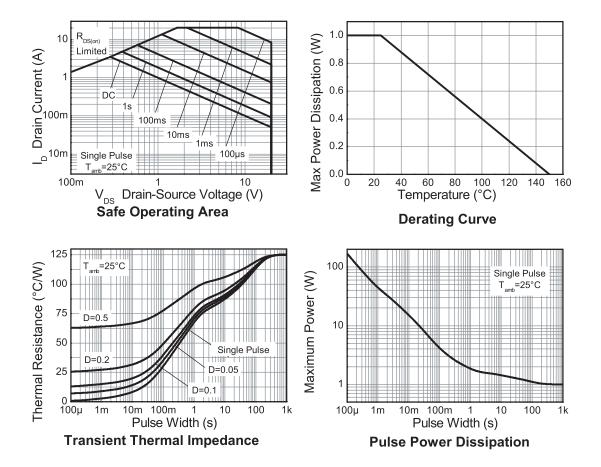
Parameter	Symbol	Limit	Unit
Junction to ambient	$R_{\ThetaJA}$	125	°C/W
Junction to ambient	$R_{\ThetaJA}$	82	°C/W

NOTES:

(a) For a device surface mounted on 25mm x 25mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions.

(b) For a device surface mounted on FR4 PCB measured at t  ${\leq}5$  sec.

(c) Repetitive rating - 25mm x 25mm FR4 PCB, D=0.02, pulse width  $300\mu s$  - pulse width limited by maximum junction temperature.



### **Thermal characteristics**

Parameter	Symbol	Min.	Тур.	Max.	Unit	Conditions
Static						
Drain-source breakdown voltage	V <sub>(BR)DSS</sub>	20			V	I <sub>D</sub> = 250μA, V <sub>GS</sub> =0V
Zero gate voltage drain current	I <sub>DSS</sub>			1	μA	V <sub>DS</sub> = 20V, V <sub>GS</sub> =0V
Gate-body leakage	I <sub>GSS</sub>			100	nA	V <sub>GS</sub> =±8V, V <sub>DS</sub> =0V
Gate-source threshold voltage	V <sub>GS(th)</sub>	0.4		1.0	V	$I_D = 250 \mu A, V_{DS} = V_{GS}$
Static drain-source on-state	R <sub>DS(on)</sub>			0.055	Ω	V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 3.5A
resistance <sup>(*)</sup>				0.075	Ω	V <sub>GS</sub> = 2.5V, I <sub>D</sub> = 3A
				0.100	Ω	V <sub>GS</sub> = 1.8V, I <sub>D</sub> = 2.6A
Forward transconductance <sup>(*) (‡)</sup>	9 <sub>fs</sub>		11		S	V <sub>DS</sub> = 10V, I <sub>D</sub> = 3.5A
Dynamic <sup>(‡)</sup>						
Input capacitance	C <sub>iss</sub>		872		pF	$V_{DS}$ = 10V, $V_{GS}$ =0V
Output capacitance	C <sub>oss</sub>		145		pF	f=1MHz
Reverse transfer capacitance	C <sub>rss</sub>		90		pF	
Switching <sup>(†)</sup> <sup>(‡)</sup>						
Turn-on-delay time	t <sub>d(on)</sub>		3.7		ns	V <sub>DD</sub> = 10V, V <sub>GS</sub> = 4.5V
Rise time	t <sub>r</sub>		5.2		ns	$I_{D}= 1A$
Turn-off delay time	t <sub>d(off)</sub>		30		ns	$R_{G} \approx 6.0\Omega$
Fall time	t <sub>f</sub>		5.5		ns	
Total gate charge	Qg		11		nC	V <sub>DS</sub> = 10V, V <sub>GS</sub> = 4.5V
Gate-source charge	Q <sub>gs</sub>		1.4		nC	I <sub>D</sub> = 4.0A
Gate drain charge	Q <sub>gd</sub>		2.1		nC	
Source-drain diode						
Diode forward voltage <sup>(*)</sup>	V <sub>SD</sub>		0.69	0.95	V	T <sub>j</sub> =25°C, I <sub>S</sub> = 1.45A, V <sub>GS</sub> =0V
Reverse recovery time <sup>(‡)</sup>	t <sub>rr</sub>		9.4		ns	T <sub>j</sub> =25°C, I <sub>F</sub> = 2.4A,
Reverse recovery charge <sup>(‡)</sup>	Q <sub>rr</sub>		2.8		nC	di/dt=100A/μs

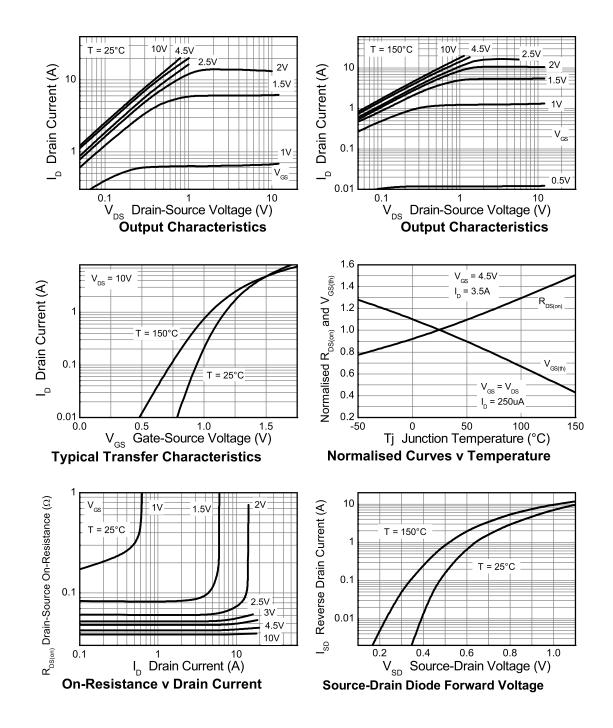
## Electrical characteristics (at $T_{amb}$ = 25°C unless otherwise stated)

NOTES:

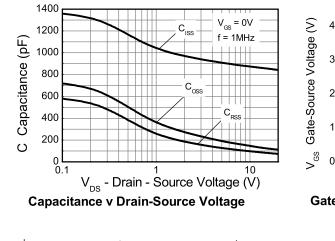
(\*) Measured under pulsed conditions. Pulse width  $\leq$ 300 $\mu$ s; duty cycle  $\leq$ 2%.

(†) Switching characteristics are independent of operating junction temperature.

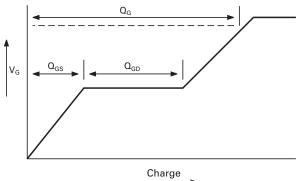
(‡) For design aid only, not subject to production testing.



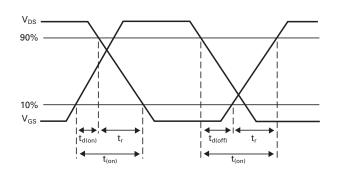
## **Typical characteristics**



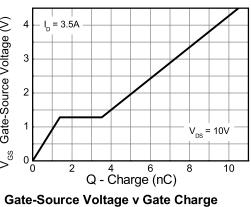


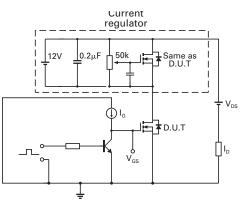


Basic gate charge waveform

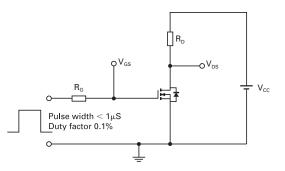


Switching time waveforms



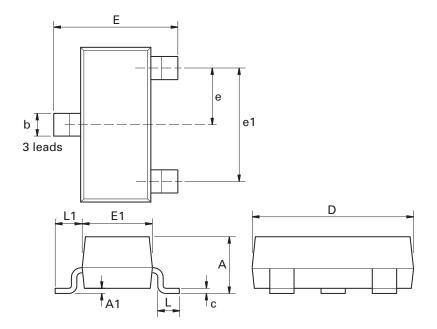


Gate charge test circuit



Switching time test circuit

## Package outline - SOT23



Dim.	Millin	neters	Inc	hes	Dim.	Millimeters		Inches	
	Min.	Max.	Min.	Max.		Min.	Max.	Max.	Max.
А	-	1.12	-	0.044	e1	1.90	NOM	0.075	NOM
A1	0.01	0.10	0.0004	0.004	E	2.10	2.64	0.083	0.104
b	0.30	0.50	0.012	0.020	E1	1.20	1.40	0.047	0.055
С	0.085	0.120	0.003	0.008	L	0.25	0.62	0.018	0.024
D	2.80	3.04	0.110	0.120	L1	0.45	0.62	0.018	0.024
е	0.95	NOM	0.0375	NOM	-	-	-	-	-

Note: Controlling dimensions are in millimeters. Approximate dimensions are provided in inches

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